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TR	ANSMITT	AL	Application Numbe	r	09/920,341			
	FORM		Filing Date		Aug 1, 2001			
(to be used fo	r all correspondence after	initial filing)	First Named Invent	or	Choi, Byung J.			
			Group Art Unit		1724			
Examiner Name Unassigned								
Total Nu	mber of Pages in This Sul	omission	Attorney Docket Nun	nber	PA17-07V06			
		ENCLOSURES	(check all that apply	<u>v)</u>				
Fee Trans	mittal Form	Assignr (for an a	nent Papers Application)		After Allowance Communication to Group			
Fee	Attached	Drawing	g(s)		Appeal Communication to Board of Appeals and Interferences			
Amendme	nt / Reply	Licensi	ng-related Papers		Appeal Communication to Group (Appeal Notice, Brief, Reply Brief)			
Afte	r Final	Petition			Proprietary Information			
Affi	davits/declaration(s)		to Convert to a anal Application		Status Letter			
Extension	Power of	of Attorney, Revocation of Correspondence	X	Other Enclosure(s) (please identify below):				
Express A	pandonment Request	l —	al Disclaimer		Form PTO-1449 with eight (8) references			
Information	Disclosure Statement	Reques	st for Refund		2. Search Report			
Certified C	opy of Priority s)	CD, Nu	mber of CD(s)		Return Receipt Postcard to Kenneth C. Brooks			
Response Incomplete	to Missing Parts/ Application	Remarks		<u>'</u>				
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Individual name	Kenneth C. Brooks		. <u>. </u>		<u> </u>			
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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

PATENT APPLICATION

Applicant: Choi et al.

Group Art Unit: 1724

Serial No.: 09/920,341

Examiner: Unassigned

Filing Date: August 1, 2001

Examiner. Unassigned

For: METHODS FOR HIGH-PRECISION GAP AND ORIENTATION SENSING BETWEEN A TRANSPARENT TEMPLATE AND SUBSTRATE FOR IMPRINT

LITHOGRAPHY

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents Washington, D.C. 20231

Sir:

The references cited on attached form PTO-1449 are being called to the attention of the Examiner. A copy of each is enclosed. Also enclosed is a copy of the Search/Examination report from the International Searching Authority, concerning a corresponding international patent application.

It is respectfully requested that the cited information be expressly considered during the prosecution of this application, and the references be made of record therein and appear among the "references cited" on any patent to issue therefrom.

Applicants state as follows:

Each Item of Information contained in this Information
Disclosure Statement was cited in a communication from a foreign
patent office in a counterpart foreign application not more than
three months prior to the filing of this Information Disclosure
Statement.

U.S. PATENT DOCUMENTS

Patent No.	Inventor	Grant Date
5,218,193	Miyatake	Jun. 8, 1993
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FOREIGN PATENT DOCUMENTS

Publication No.	Inventor	Publication Date		
WO 87/02935	Long et al.	May 21, 1987		
JP 02192045	Mineo et al.	Jul. 27, 1990		
EP 0867775	Shinji	Sep. 30, 1998		

NON PATENT DOCUMENTS

Norio Uchida et al., "A Mask-to-Wafer Alignment and Gap Setting Method for X-Ray Lithography Using Gratings" Journal of Vacuum Science and Technology, Part B, American Institute of Physics, New York, US, vol. 9, no. 6, pages 3203-3204, November 1, 1991.

White et al., "Novel alignment system for imprint lithography" 44th International Conference on Electron, Ion, and Photon Beam Technology and Nanofabrication, Rancho Mirage, CA, USA, May 30-June 2, vol. 18, no. 6, pages 3552-3556, Journal of Vacuum Science and Technology, Part B, November 2000.

CERTIFICATE OF MAILING I hereby certify that this paper (along with any paper referred to as being attached or enclosed) is being deposited with the United States Postal Service on the date shown below with sufficient postage as first class mail in an envelope addressed to : BOX PATENT APPLICATION, Commissioner

Respectfully Submitted,

Kenneth C. Brooks Req. No. 38,393

DEC 0 9

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Sheet	1	of	2	Attorney Docket Number	PA17-07V06

				U.S. PATENT DOCUMEN	TS	
Examiner Initials*	Cite No.1	U.S. Patent Do	Kind Code ² (if known)	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
	BI	5,218,193	T	Miyatake	06-08-1993	
	B2	5,355,219		Araki et al.	10-11-1994	
	B3	6,088,103		Everett et al.	07-11-2000	
						
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	FOREIGN PATENT DOCUMENTS										
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Examiner Initials*	Cite No. ¹	Office ³	Number⁴	Kind Code⁵ (<i>if known</i>)	Name of Patentee or Applicant of Cited Document	Cited Document MM-DD-YYYY	Where Relevant Passages or Relevant Figures Appear	Τ ⁶			
	B4	wo	87/02935		Long et al.	05-21-1987		Γ			
-	B5	JP	02192045		Mineo et al.	07-27-1990					
	B6	ΕP	0867775		Shinji	09-30-1998					
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¹Unique citation designation number. ²See attached Kinds of U.S. Patent Documents. ³Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶Applicant is to place a check mark here if English language Translation is attached.

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	Substitu	ute for form 1449B/P	то		Complete if Known		
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	Sheet	2	of	2	Attorney Docket Number	PA17-07V06	

OTHER PRIC	OR ART -	NON PATENT LITERATURE DOCUMENTS
Examiner Initials*	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.
	B7	publisher, city and/or country where published. Norio Uchida et al., "A Mask-to-Wafer Alignment and Gap Setting Method for X-Ray Lithography Using Gratings" Journal of Vacuum Science and Technology, Part B, American Institute of Physics. New York, US, vol 9, no. 6, pages 3203-3204, November 1, 1991.
	B8	White et al., "Novel alignment system for imprint lithography" 44 th International Conference on Electron, Ion, and Photon Beam Technology and Nanofabrication, Rancho Mirage, CA, USA, May 30-June 2, vol. 18, no. 6, pages 3552-3556, Journal of Vacuum Science and Technology, Part B, November 2000.
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